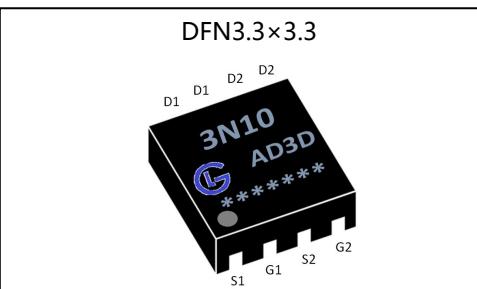


General Description:

The GL3N10AD3D uses advanced trench technology and design to provide excellent RDS(ON) with low gate charge. It can be used in a wide variety of applications. The package form is DFN3.3*3.3, which accords with the RoHS standard.

V_{DSS}	100	V
I_D	3	A
P_D	1.3	W
$R_{DS(ON)}$ TYPE	0.155	Ω

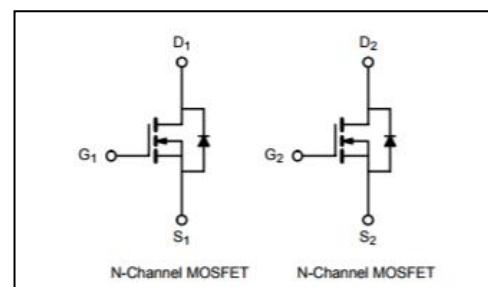


Features:

- Fast Switching
- Low Gate Charge and Rdson
- Low Reverse transfer capacitances
- 100% Single Pulse avalanche energy Test

Applications:

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply



Absolute (Tc= 25°C unless otherwise specified):

Symbol	Parameter	Rating	Units
V_{DSS}	Drain-to-Source Voltage	100	V
I_D	Continuous Drain Current	3.0	A
	Continuous Drain Current $T_c = 100^\circ C$	1.7	A
I_{DM}^{a1}	Pulsed Drain Current	12	A
V_{GS}	Gate-to-Source Voltage	± 20	V
E_{AS}^{a2}	Single Pulse Avalanche Energy	50	mJ
E_{AR}^{a1}	Avalanche Energy ,Repetitive	1.25	mJ
I_{AR}^{a1}	Avalanche Current	1.8	A
d_v/d_t^{a3}	Peak Diode Recovery dv/dt	5.0	V/ns
P_D	Power Dissipation	1.5	W
T_J, T_{stg}	Operating Junction and Storage Temperature Range	150, -55 to 175	°C
T_L	Maximum Temperature for Soldering	300	°C



GL3N10AD3D

GL Silicon N-Channel Power MOSFET

Electrical Characteristics ($T_c=25^\circ C$ unless otherwise specified):

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V_{DSS}	Drain to Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	100	--	--	V
$\Delta V_{DSS}/\Delta T_J$	Bvdss Temperature Coefficient	$I_D=250\mu A$, Reference $25^\circ C$	--	0.1	--	$V/^\circ C$
I_{DSS}	Drain to Source Leakage Current	$V_{DS}=100V, V_{GS}= 0V, T_a=25^\circ C$	--	--	1	μA
		$V_{DS}=80V, V_{GS}= 0V, T_a=125^\circ C$	--	--	250	
$I_{GSS(F)}$	Gate to Source Forward Leakage	$V_{GS}=+20V$	--	--	100	nA
$I_{GSS(R)}$	Gate to Source Reverse Leakage	$V_{GS}=-20V$	--	--	-100	nA

ON Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$R_{DS(ON)}$	Drain-to-Source On-Resistance	$V_{GS}=10V, I_D=3.0A$	--	155	185	$m\Omega$
$R_{DS(ON)}$	Drain-to-Source On-Resistance	$V_{GS}=6V, I_D=2.5A$	--	175	210	$m\Omega$
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	1.0	--	3.0	V
Pulse width $t_p \leq 380\mu s, \delta \leq 2\%$						

Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
g_{fs}	Forward Transconductance	$V_{DS}=5V, I_D=3A$	4	--	--	S
C_{iss}	Input Capacitance	$V_{GS}=0V, V_{DS}=50V$	--	510	--	pF
C_{oss}	Output Capacitance	$f=1.0MHz$	--	18	--	
C_{rss}	Reverse Transfer Capacitance		--	15	--	

Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$t_{d(ON)}$	Turn-on Delay Time	$I_D=3.0A, V_{DD}=50V$	--	7	--	ns
t_r	Rise Time		--	5	--	
$t_{d(OFF)}$	Turn-Off Delay Time		--	20	--	
t_f	Fall Time		--	5	--	
Q_g	Total Gate Charge	$I_D=3A, V_{DD}=50V$	--	15	--	nC
Q_{gs}	Gate to Source Charge		--	1.6	--	
Q_{gd}	Gate to Drain ("Miller")Charge		--	2.5	--	

Source-Drain Diode Characteristics

Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
I_S	Continuous Source Current (Body Diode)		--	--	3	A
I_{SM}	Maximum Pulsed Current (Body Diode)		--	--	12	A
V_{SD}	Diode Forward Voltage	$I_S=3.0A, V_{GS}=0V$	--	--	1.5	V
t_{rr}	Reverse Recovery Time	$I_S=3.0A, T_J=25^{\circ}C$	--	50	--	ns
Q_{rr}	Reverse Recovery Charge	$dI_F/dt=100A/\mu s, V_{GS}=0V$	--	180	--	nC

 Pulse width $t_p \leq 380\mu s, \delta \leq 2\%$

Symbol	Parameter	Typ.	Units
$R_{\theta JC}$	Junction-to-Case	4.5	°C/W
$R_{\theta JA}$	Junction-to-Ambient	83	°C/W

^{a1}: Repetitive rating; pulse width limited by maximum junction temperature

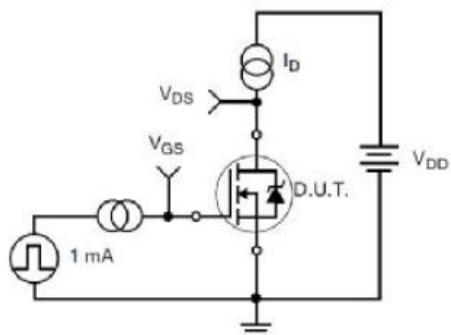
^{a2}: $L=10.0mH, I_D=0.5A$, Start $T_J=25^{\circ}C$
^{a3}: $I_{SD}=3A, dI/dt \leq 100A/\mu s, V_{DD} \leq BV_{DS}$, Start $T_J=25^{\circ}C$
Test Circuit and Waveform


Figure 17. Gate Charge Test Circuit

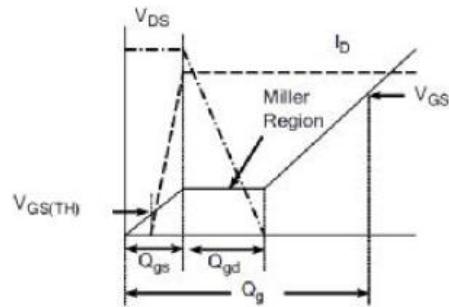


Figure 18. Gate Charge Waveform

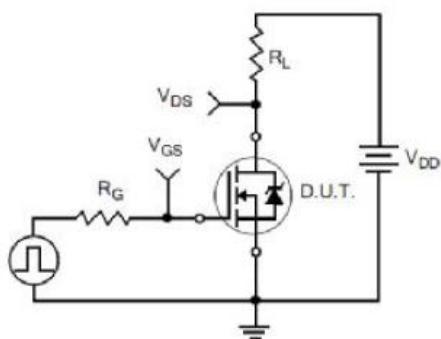


Figure 19. Resistive Switching Test Circuit

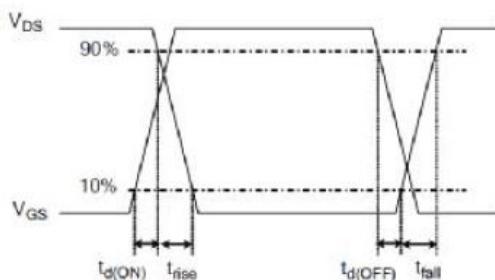
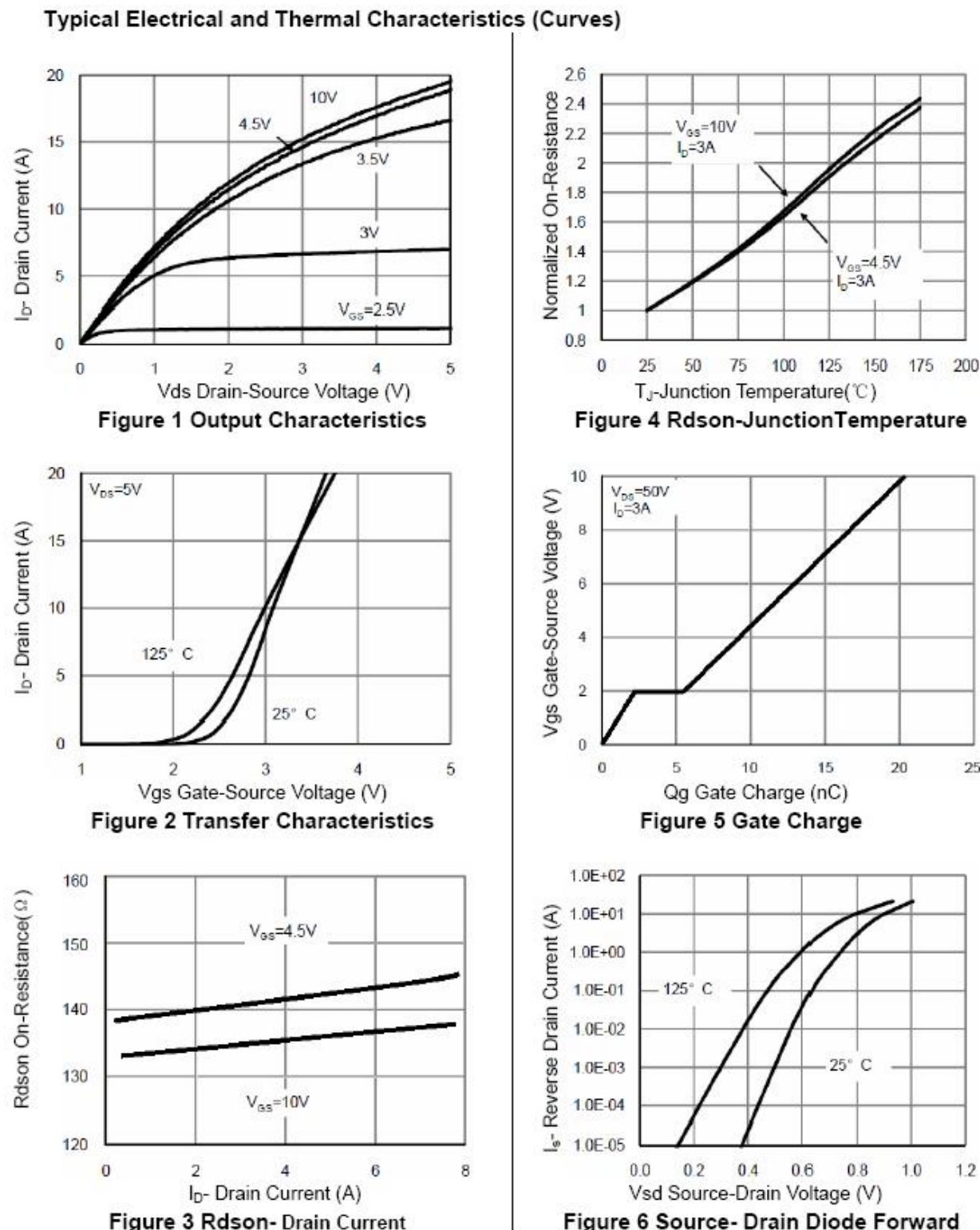


Figure 20. Resistive Switching Waveforms



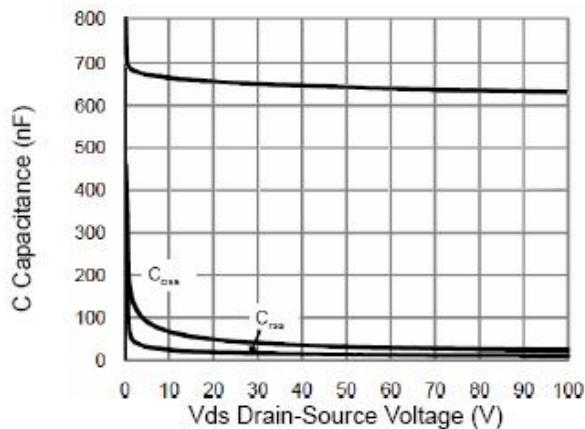


Figure 7 Capacitance vs Vds

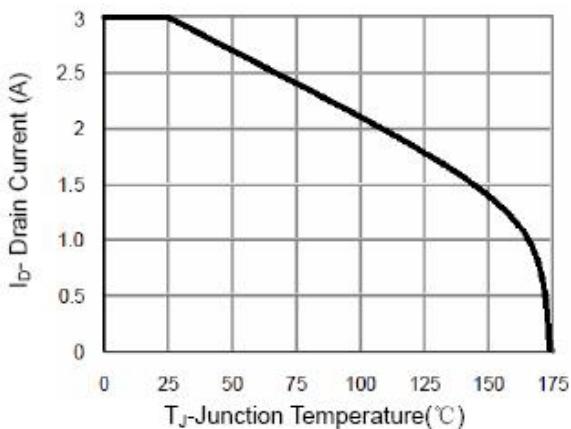


Figure 9 BV_{DSS} vs Junction Temperature

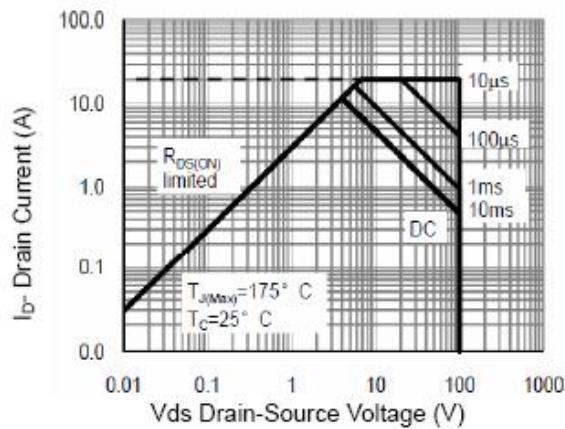


Figure 8 Safe Operation Area

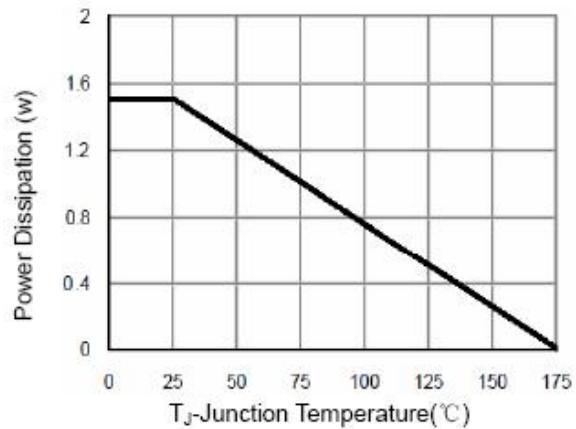


Figure 10 Power De-rating

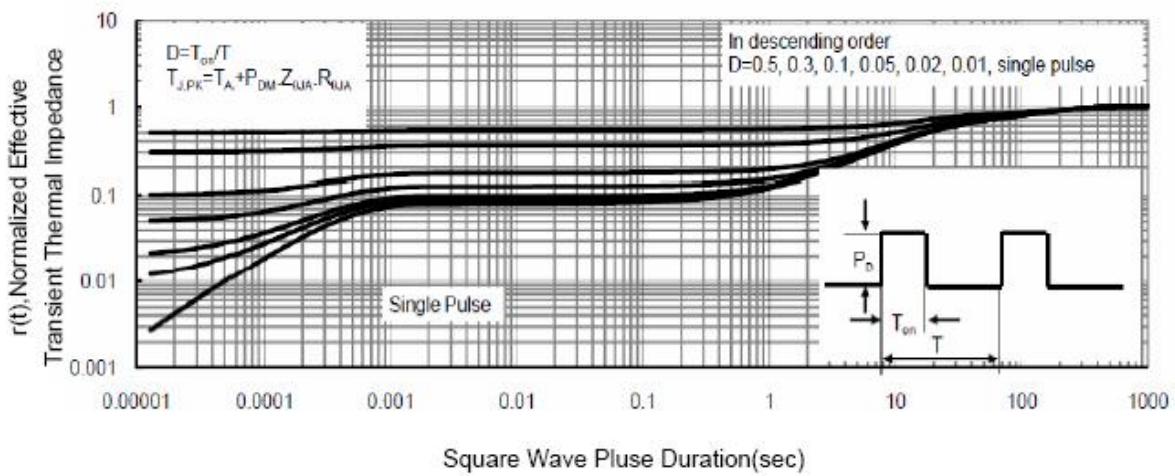


Figure 11 Normalized Maximum Transient Thermal Impedance